

Philippe H Goudeau

List of Publications by Citations

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35
papers

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ext. papers

289
ext. citations

2.4
avg, IF

2.79
L-index

#	Paper	IF	Citations
35	Combined synchrotron X-ray and image-correlation analyses of biaxially deformed W/Cu nanocomposite thin films on Kapton. <i>Journal of Applied Crystallography</i> , 2011 , 44, 1071-1079	3.8	32
34	Study on Young's modulus of thin films on Kapton by microtensile testing combined with dual DIC system. <i>Surface and Coatings Technology</i> , 2016 , 308, 273-279	4.4	23
33	Reverse engineering the ancient ceramic technology based on X-ray fluorescence spectromicroscopy. <i>Journal of Analytical Atomic Spectrometry</i> , 2011 , 26, 969	3.7	22
32	Mesoscale x-ray diffraction measurement of stress relaxation associated with buckling in compressed thin films. <i>Applied Physics Letters</i> , 2003 , 83, 51-53	3.4	21
31	Ceramics in art and archaeology: a review of the materials science aspects. <i>European Physical Journal B</i> , 2015 , 88, 1	1.2	18
30	Complementary use of monochromatic and white-beam X-ray micro-diffraction for the investigation of ancient materials. <i>Journal of Applied Crystallography</i> , 2015 , 48, 1522-1533	3.8	17
29	Evolution of terra sigillata technology from Italy to Gaul through a multi-technique approach. <i>Journal of Analytical Atomic Spectrometry</i> , 2015 , 30, 658-665	3.7	17
28	Benefits of two-dimensional detectors for synchrotron X-ray diffraction studies of thin film mechanical behavior. <i>Journal of Applied Crystallography</i> , 2008 , 41, 1076-1088	3.8	14
27	Strain transfer through film-substrate interface and surface curvature evolution during a tensile test. <i>Applied Surface Science</i> , 2018 , 434, 771-780	6.7	11
26	Investigation of buckling transition from straight-sided to telephone-cord wrinkles in Al films. <i>Journal of Micromechanics and Microengineering</i> , 2013 , 23, 045014	2	11
25	Elastic behaviour of titanium dioxide films on polyimide substrates studied by in situ tensile testing in a X-ray diffractometer. <i>Nuclear Instruments & Methods in Physics Research B</i> , 2010 , 268, 365-369	1.2	11
24	Physical origin of spontaneous interfacial alloying in immiscible W/Cu multilayers. <i>Journal of Materials Science</i> , 2007 , 42, 7446-7450	4.3	10
23	Mastering the biaxial stress state in nanometric thin films on flexible substrates. <i>Applied Surface Science</i> , 2014 , 306, 70-74	6.7	8
22	Correlation Between Processing and Properties of Titanium Oxycarbide, TiCxOy, Thin Films. <i>Plasma Processes and Polymers</i> , 2007 , 4, S83-S88	3.4	7
21	Cyclic testing of thin Ni films on a pre-tensile compliant substrate. <i>Materials Science & Engineering A: Structural Materials: Properties, Microstructure and Processing</i> , 2017 , 695, 112-119	5.3	6
20	Residual stress determination in oxide layers at different length scales combining Raman spectroscopy and X-ray diffraction: Application to chromia-forming metallic alloys. <i>Journal of Applied Physics</i> , 2017 , 122, 195105	2.5	6
19	Frequency analysis for investigation of the thermomechanical mechanisms in thermal oxides growing on metals. <i>Acta Mechanica</i> , 2017 , 228, 3595-3617	2.1	4

18	Stress Relaxation Related to Spontaneous Thin Film Buckling: Correlation between Finite Element Calculations and Micro Diffraction Analysis. <i>Quantum Beam Science</i> , 2019 , 3, 1	1.6	3
17	External Reference Samples for Residual Stress Analysis by X-Ray Diffraction. <i>Materials Science Forum</i> , 2011 , 681, 215-222	0.4	3
16	Mechanical Properties of Thin Films and Nanometric Multilayers Using Tensile Testing and Synchrotron X-Ray Diffraction. <i>Plasma Processes and Polymers</i> , 2007 , 4, 311-317	3.4	3
15	Determination of Residual Stresses in an Oxidized Metallic Alloy under Thermal Loadings. <i>Metals</i> , 2018 , 8, 913	2.3	3
14	Viscoplasticity and growth strain parameters identification by full modelling optimization during the high temperature oxidation of Ni28Cr modified by the reactive element yttria or zirconium. <i>Computational Materials Science</i> , 2020 , 180, 109689	3.2	2
13	Non-equibiaxial deformation of W/Cu nanocomposite thin films on stretchable substrate: Effect of loading path. <i>Thin Solid Films</i> , 2013 , 549, 239-244	2.2	2
12	Modelling of the Mechanical Behaviour of a Chromia Forming Alloy Under Thermal Loading. <i>Oxidation of Metals</i> , 2017 , 88, 15-27	1.6	2
11	Macro Stress Mapping on Thin Film Buckling. <i>Materials Science Forum</i> , 2002 , 404-407, 709-714	0.4	2
10	Elastic property determination of nanostructured W/Cu multilayer films on a flexible substrate. <i>Acta Mechanica Sinica/Lixue Xuebao</i> , 2019 , 35, 1210-1216	2	1
9	Strains in Thermally Growing Cr2O3 Films Measured In Situ Using Synchrotron X-Rays. <i>Materials Science Forum</i> , 2017 , 905, 52-59	0.4	1
8	Application of the White/Monochromatic X-Ray Diffraction Technique to the Study of Texture and Triaxial Strain at the Submicron Level. <i>Materials Science Forum</i> , 2005 , 490-491, 672-677	0.4	1
7	Relationship between Nitrogen Content and Mechanical Properties in Al1-xCrxFy Thin Films. <i>Materials Science Forum</i> , 2013 , 761, 165-170	0.4	0
6	Modeling of Stress and Strain Fields Induced during the Smart-Cut Process on Silicone - Influence of Different Couplings for Diffusion of Hydrogen at a Microscopic Scale. <i>Advanced Materials Research</i> , 2014 , 996, 707-712	0.5	
5	Evolution of Solid-State Microstructures in Polycrystalline Materials: Application of High-Energy X-Ray Diffraction to Kinetic and Phase Evolution Studies 2013 , 181-219		
4	Time-Resolved X-Ray Stress Analysis in Multilayered Thin Films during Continuous Loading: Use of 2D Remote Detection. <i>Advanced Materials Research</i> , 2014 , 996, 878-883	0.5	
3	Elastic strains in polycrystalline UO2 samples implanted with He: micro Laue diffraction measurements and elastic modeling. <i>Materials Research Society Symposia Proceedings</i> , 2013 , 1514, 125-130		
2	Thermal Residual Stress Relaxation in Sputtered ZnO Film on (100) Si Substrate Studied In Situ by Synchrotron X-Ray Diffraction. <i>Materials Science Forum</i> , 2011 , 681, 127-132	0.4	
1	Machine biaxiale sur la ligne de lumière Diffabs pour l'étude des propriétés mécaniques de films minces déposés sur substrats polymères. <i>Materiaux Et Techniques</i> , 2015 , 103, 610	0.6	

